

Support Vector Machines

EECE 580B

Lecture 25

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Steganalysis

Objective

- **Traditional steganalysis:** a steganography system is considered broken, when the mere *presence* of a hidden message is detected.
- **Forensic steganalysis:** detection of the message may not be sufficient; often, other information would be useful
 - determine type of embedding algorithm (LSB, SS)
 - identify stego software used (F5, OutGuess, Steganos, ...)
 - search for stego key if necessary
 - extract hidden bitstream
 - decrypt the message (cryptanalysis)

Steganalysis

- Steganalysis is a binary hypothesis testing problem – H_0 : cover and H_1 : stego.
- If the distributions were known, Likelihood Ratio Test (LRT) would be the *optimal* detector.
- In absence of distributions, we resort to classification using machine learning.
- Output of steganalysis can be a real number, rather than binary {cover, stego}. If this number is an estimate of the message length (change rate), we speak of *quantitative steganalysis* (SVR useful here!).

Feature-based steganalysis

- Steganalyzer can be built to detect a specific stegosystem (targeted steganalyzer) or to detect an arbitrary stegosystem (universal “blind”).
- Constructing a steganalyzer involves the following steps:
 - select good features (sensitive to embedding, insensitive to image content, low dimensionality).
 - if features low-dimensional (e.g., 1D), estimate distributions, use LRT.
 - if features high-dimensional, select a machine-learning tool, e.g., SVM.
 - train SVM on a large and diverse database of cover and stego images, use a mixture of payloads.
- Caveat
 - steganalyzer will depend on the chosen features and the database (scans of photographs, decompressed JPEGs, raw never-compressed digital camera images, processed (denoised) images).

SPAM features (motivation)

Observation

- Neighboring pixels in natural images exhibit dependencies.
- Pixel noise is not iid but also dependent (and dependent on content) due to in-camera image processing, compression, etc.
- *Stego noise in LSB embedding or SSS is pixel-to-pixel independent and often idenpendent of content.*

Idea

Model dependencies between neighboring pixels and detect violations of the model due to stego noise.

Modeling dependencies between pixels (1)

Histogram of pixel pairs

The counts of neighboring pixel-pairs, triples, quadruples, ..., will capture all dependencies.

Disadvantages:

- The number of bins grows exponentially with bin size.
- Estimates of some bins may be very noisy.
- High influence of image content.

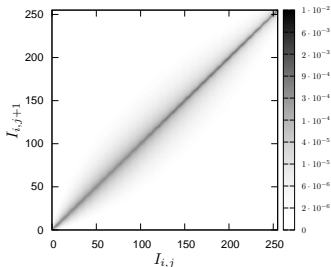


Fig: Probability of co-occurrence

Modeling dependencies between pixels (2)

Differences of pixel values

We model *differences* of pixels instead of the pixel values themselves.

Advantages:

- Image content is suppressed.
- Differences $I_{i,j+1} - I_{i,j}$ are almost independent of $I_{i,j}$.
- Simplification of the model.
- Can be modeled by Markov chains.

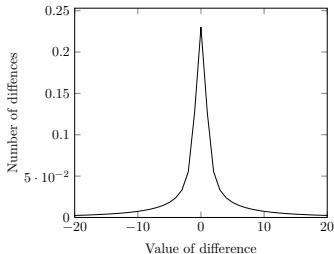
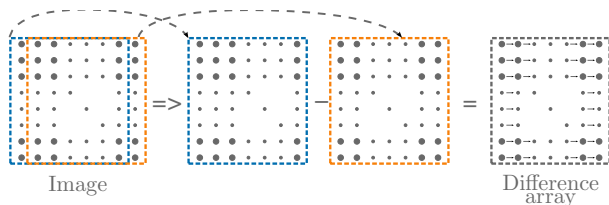


Fig: Histogram of differences

SPAM features (1)

Computing transition probabilities in the horizontal direction:



- 1 Calculate the difference array, $\mathbf{D}_{i,j}^{\rightarrow} = I_{i,j} - I_{i,j+1}$.
- 2 Truncate: if $|\mathbf{D}_{i,j}^{\rightarrow}| > T$, set $\mathbf{D}_{i,j}^{\rightarrow} = \text{sign}(\mathbf{D}_{i,j}^{\rightarrow})T$.
- 3 Compute the transition probability matrix

$$\mathbf{M}_{u,v}^{\rightarrow} = Pr(\mathbf{D}_{i,j+1}^{\rightarrow} = u | \mathbf{D}_{i,j}^{\rightarrow} = v), u, v \in \{-T, \dots, T\}$$

$$\mathbf{M}_{u,v,w}^{\rightarrow} = Pr(\mathbf{D}_{i,j+2}^{\rightarrow} = u | \mathbf{D}_{i,j+1}^{\rightarrow} = v, \mathbf{D}_{i,j}^{\rightarrow} = w), u, v, w \in \{-T, \dots, T\}$$

SPAM features (2)

- 1 Transition matrices \mathbf{M} are calculated along 8 directions
 $\leftarrow, \rightarrow, \downarrow, \uparrow, \swarrow, \searrow, \nearrow, \nwarrow$
- 2 Features \mathbf{F} are formed from \mathbf{M} by averaging to reduce dimensionality

$$\mathbf{F}_{1,\dots,k} = \frac{1}{4} \left[\mathbf{M}_{\rightarrow} + \mathbf{M}_{\leftarrow} + \mathbf{M}_{\downarrow} + \mathbf{M}_{\uparrow} \right],$$
$$\mathbf{F}_{k+1,\dots,2k} = \frac{1}{4} \left[\mathbf{M}_{\swarrow} + \mathbf{M}_{\searrow} + \mathbf{M}_{\nearrow} + \mathbf{M}_{\nwarrow} \right].$$

- 3 The total number of features is $\dim = 2(2T + 1)^2$.
- 4 In your final project, $T = 4 \Rightarrow \dim = 2 \times 9^2 = 162$.

Comparison to prior art

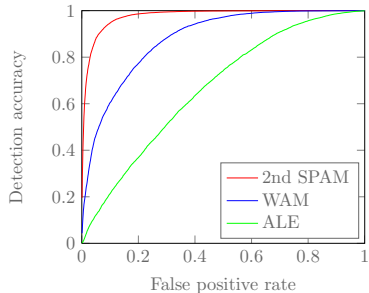


Fig: Payload 0.25 bits per pixel

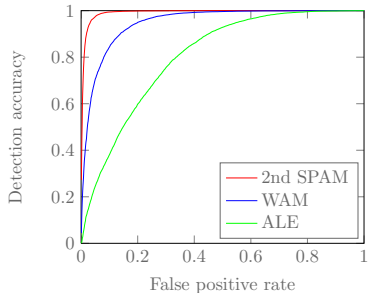


Fig: Payload 0.5 bits per pixel.